



### FEATURES

- On-Chip Latches for All DAC's
- Linearity Grades to  $\pm 1/8$  LSB
- Single Supply Voltage (5 Volt)
- DAC's Matched to 1%
- Four Quadrant Multiplication
- Microprocessor TTL/CMOS Compatible
- Read/Write Capability for all DAC's

### APPLICATIONS

- Microprocessor Controlled Gain and Attenuation Circuits
- Microprocessor Controlled/Programmable Power Supplies
- Hardware Redundant Applications Requiring Data Readback
- PDIP, CDIP, PLCC & SOIC Packages Available

### GENERAL DESCRIPTION

The MP7628 is a monolithic quad 8-bit digital-to-analog converter designed using Micro Power Systems' proven decoded DAC architecture featuring excellent DAC-to-DAC matching and guaranteed monotonicity.

Separate on-chip latches are provided for each DAC to allow easy microprocessor interface.

The readback function allows the user to poll or read the data latches, eliminating the need for storing information in RAM. In the event the microprocessor power supply is interrupted, it can poll the DACs to establish the last known system state.

Data is transferred into any of the four DAC data latches via common 8-bit TTL/CMOS compatible input port. Control inputs

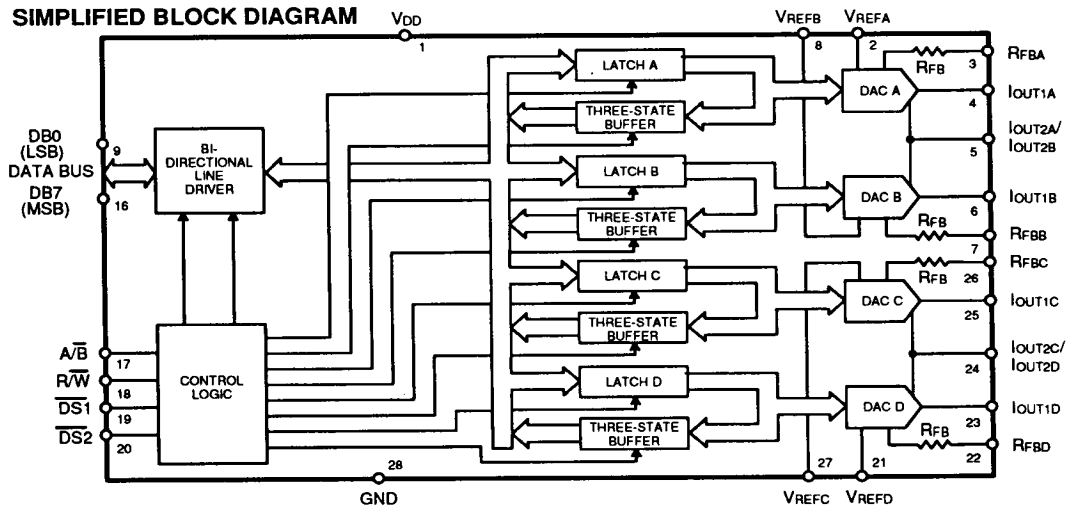
$\overline{DS1}$ ,  $\overline{DS2}$  and  $A/\overline{B}$  determine which DAC is to be loaded. The MP7628's load cycle is similar to the write cycle of a random access memory and the device is bus compatible with most 8-bit microprocessors.

The device operates at +5 V power supply and dissipates less than 5mW.

All DAC's offer excellent four quadrant multiplication characteristics with a separate reference input and feedback resistor for each DAC.

Specified for operation over the commercial / industrial (-40 to +85°C) and military (-55 to +125°C) temperature ranges, the MP7628 is available in Plastic and Ceramic dual-in-line, Plastic leaded chip carrier (PLCC) and Surface Mount (SOIC) packages.

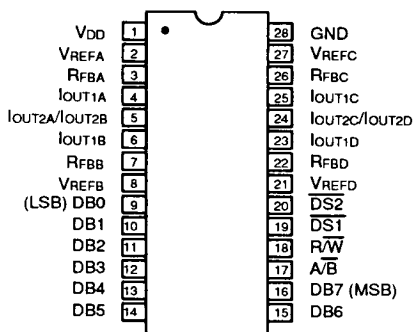
### SIMPLIFIED BLOCK DIAGRAM



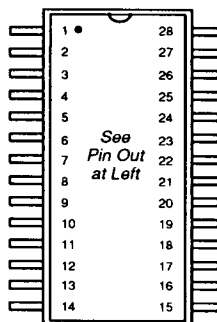
## ORDERING INFORMATION

Package Type	Temperature Range	Part No.	Relative Accuracy	Differential Non-Linearity	Gain Error
Plastic Dip	-40 to +85°C	MP7628JN	±1/2 LSB	±1/2 LSB	±1.8% FSR
Plastic Dip	-40 to +85°C	MP7628KN	±1/4 LSB	±1/4 LSB	±0.9% FSR
Plastic Dip	-40 to +85°C	MP7628LN	±1/8 LSB	±1/8 LSB	±0.5% FSR
SOIC	-40 to +85°C	MP7628JS	±1/2 LSB	±1/2 LSB	±1.8% FSR
SOIC	-40 to +85°C	MP7628KS	±1/4 LSB	±1/4 LSB	±0.9% FSR
SOIC	-40 to +85°C	MP7628LS	±1/8 LSB	±1/8 LSB	±0.5% FSR
PLCC	-40 to +85°C	MP7628JP	±1/2 LSB	±1/2 LSB	±1.8% FSR
PLCC	-40 to +85°C	MP7628KP	±1/4 LSB	±1/4 LSB	±0.9% FSR
PLCC	-40 to +85°C	MP7628LP	±1/8 LSB	±1/8 LSB	±0.5% FSR
Ceramic Dip	-40 to +85°C	MP7628AD	±1/2 LSB	±1/2 LSB	±1.8% FSR
Ceramic Dip	-40 to +85°C	MP7628BD	±1/4 LSB	±1/4 LSB	±0.9% FSR
Ceramic Dip	-40 to +85°C	MP7628CD	±1/8 LSB	±1/8 LSB	±0.5% FSR
Ceramic Dip	-55 to +125°C	MP7628SD	±1/2 LSB	±1/2 LSB	±1.8% FSR
Ceramic Dip	-55 to +125°C	MP7628SD/883	±1/2 LSB	±1/2 LSB	±1.8% FSR
Ceramic Dip	-55 to +125°C	MP7628TD	±1/4 LSB	±1/4 LSB	±0.9% FSR
Ceramic Dip	-55 to +125°C	MP7628TD/883	±1/4 LSB	±1/4 LSB	±0.9% FSR
Ceramic Dip	-55 to +125°C	MP7628UD	±1/8 LSB	±1/8 LSB	±0.5% FSR
Ceramic Dip	-55 to +125°C	MP7628UD/883	±1/8 LSB	±1/8 LSB	±0.5% FSR

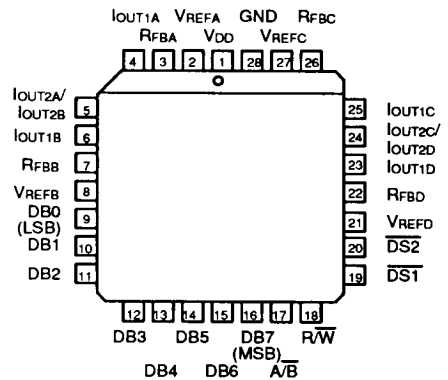
## PIN CONFIGURATIONS



28 Pin CDIP, PDIP (0.600")



28 Pin SOIC (Jedec, 0.300")



28 Pin PLCC



PIN OUT DEFINITIONS

PIN NO.	NAME	DESCRIPTION
1	VDD	Power Supply
2	VREFA	Reference Voltage for DAC A
3	RFB A	Feedback Resistor for DAC A
4	IOUT1A	Current Output 1 DAC A
5	IOUT2A/ IOUT2B	Current Output 2 DAC A/DAC B
6	IOUT1B	Current Output 1 DAC B
7	RFB B	Feedback Resistor for DAC B
8	VREFB	Reference Voltage for DAC B
9	DB0	Data Bit 0 (LSB)
10	DB1	Data Bit 1
11	DB2	Data Bit 2
12	DB3	Data Bit 3
13	DB4	Data Bit 4
14	DB5	Data Bit 5
15	DB6	Data Bit 6
16	DB7	Data Bit 7 (MSB)
17	A/B	DAC Selection
18	R/W	Read/Write
19	DS1	Control 1
20	DS2	Control 2
21	VREFD	Reference Voltage for DAC D
22	RFB D	Feedback Resistor for DAC D
23	IOUT1D	Current Output 1 DAC D
24	IOUT2C/ IOUT2D	Current Output 2 DAC C/DAC D
25	IOUT1C	Current Output 1 DAC C
26	RFB C	Feedback Resistor for DAC C
27	VREFC	Reference Voltage for DAC C
28	GND	Ground

## ELECTRICAL CHARACTERISTICS

(VDD = + 5 V, VREF = +10 V unless otherwise noted)

Parameter	Symbol	25°C			Tmin to Tmax		Units	Test Conditions/Comments
		Min	Typ	Max	Min	Max		
<b>STATIC PERFORMANCE (1)</b>								
Resolution (All Grades)	N	8			8		Bits	FSR = Full Scale Range
Integral Non-Linearity (Relative Accuracy)	INL						LSB	End Point Linearity Spec.
J, A, S				±1/2		±1/2		
K, B, T				±1/4		±1/4		
L, C, U				±1/8		±1/8		
Differential Non-Linearity	DNL						LSB	All grades monotonic over full temperature range.
J, A, S				±1/2		±1/2		
K, B, T				±1/4		±1/4		
L, C, U				±1/8		±1/8		
Gain Error	GE						% FSR	Using Internal RFB Digital Inputs = VINH
J, A, S				±1.5		±1.8		
K, B, T				±0.8		±0.9		
L, C, U				±0.4		±0.5		
Gain Temperature Coefficient (2)	TCGE						2 ppm/°C	ΔGain/ΔTemperature
Power Supply Rejection Ratio	PSRR			±200		±400	ppm/%	ΔGain/ΔVDD  ΔVDD = ± 5% Digital Inputs = VINH
Output Leakage Current (all)	IOUT1			±50		±200	nA	Digital Inputs = VINL
<b>REFERENCE INPUT</b>								
Voltage Range (2)				±20		±20	V	
Input Resistance	RIN	12		28	12	28	KΩ	
<b>DIGITAL INPUTS</b>								
Logic Thresholds								
VINH		2.4			2.4		V	
VINL				0.8		0.8	V	
Input Leakage Current	ILKG			±1		±10	μA	
Input Capacitance (2)	CIN		3				pF	
<b>DATA BUS OUTPUTS</b>								
Output Capacitance (2)	COUT		7				pF	
Input Leakage Current	ILKG			±1		±10	μA	
<b>ANALOG OUTPUTS</b>								
Propagation Delay (2)		500			750		ns	From digital input to 90% of final analog output current
Output Capacitance (2)	COUT		120				pF	DAC Inputs all 1's
	COUT		80				pF	DAC Inputs all 0's
Glitch Energy (2)		160			440		nVs	Typical for code transition from all 0's to all 1's



ELECTRICAL CHARACTERISTICS (CON'T)

Parameter	Symbol	Min	25°C Typ	Max	Tmin to Min	Tmax Max	Units	Test Conditions/Comments
<b>POWER SUPPLY (5)</b>								
Functional Voltage Range (2)	V <sub>DD</sub>	4.5		5.5	4.5	5.5	V	All digital inputs = 0 V or all = 5 V
Supply Current	I <sub>DD</sub>			50		50	µA	
<b>SWITCHING CHARACTERISTICS (2, 4)</b>								
Data Write Time	t <sub>w</sub>	320			400		ns	
Write Strobe Req.	t <sub>DSW</sub>	200			250		ns	
Data Hold Time	t <sub>DHLD</sub>	40			50		ns	
Data Read Time	t <sub>r</sub>	480			600		ns	
Tri-State Hold Time	t <sub>TSHD</sub>	240			300		ns	
Read Strobe Req.	t <sub>DSR</sub>	320			400		ns	

NOTES:

- (1) Full Scale Range (FSR) is 10V for unipolar mode and ±10V for bipolar.
- (2) Guaranteed but not production tested.
- (3) Digital input levels should not go below ground or exceed the positive supply voltage, otherwise damage may occur.
- (4) See timing diagram.
- (5) Specified values guarantee functionality. Refer to other parameters for accuracy.

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Specifications are subject to change without notice

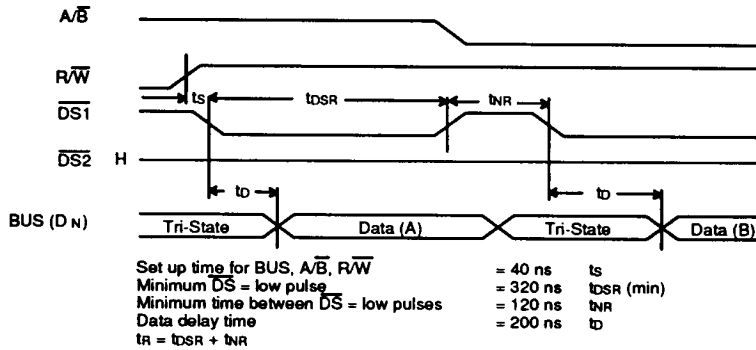
ABSOLUTE MAXIMUM RATINGS (1, 2) (TA = +25°C unless otherwise noted)

V <sub>DD</sub> to GND	+7 V	Storage Temperature	-65°C to +150°C
Digital Input Voltage to GND (2)	GND -0.5 to V <sub>DD</sub> +0.5 V	Lead Temperature (Soldering, 10 seconds)	+300°C
I <sub>OUT1</sub> , I <sub>OUT2</sub> to GND (2)	GND -0.5 to V <sub>DD</sub> +0.5 V	Package Power Dissipation Rating to 75°C	
V <sub>REF</sub> to GND	±25 V	CDIP, PDIP, SOIC, PLCC	450mW
V <sub>RFB</sub> to GND	±25 V	Derates above 75°C	6mW/°C

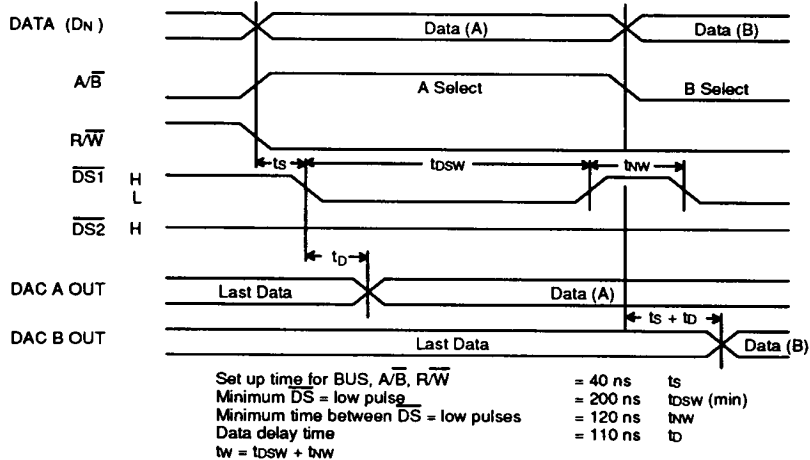
NOTES:

- (1) Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.
- (2) Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies.

## TIMING DIAGRAM READ CYCLE



## TIMING DIAGRAM WRITE CYCLE



## MODE SELECTION TABLE

DS1	DS2	A/B	R/W	MODE	DAC
L	H	H	L	WRITE	A
L	H	L	L	WRITE	B
H	L	H	L	WRITE	C
H	L	L	L	WRITE	D
L	H	H	H	READ	A
L	H	L	H	READ	B
H	L	H	H	READ	C
H	L	L	H	READ	D
L	L	H	L	WRITE	A & C
L	L	L	L	WRITE	B & D
H	H	X	X	HOLD	A/B/C/D
L	L	H	H	HOLD	A/B/C/D
L	L	L	H	HOLD	A/B/C/D

L = LOW STATE  
 H = HIGH STATE  
 X = DON'T CARE



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**INTERFACE LOGIC INFORMATION**

**DAC Selection:** All DAC latches share a common 8-bit input port. The control inputs  $\overline{DS1}$ ,  $\overline{DS2}$   $A/\overline{B}$  select which DAC can accept data from the input port.

**Mode Selection:** Inputs  $\overline{DS}$  and  $R/\overline{W}$  control the operating mode of the selected DAC. See *Mode Selection Table on the previous page*.

**Write Mode:** When  $\overline{DS}$  and  $R/\overline{W}$  are both low the selected DAC is in the write mode. The input data latches of the selected

DAC are transparent and its analog output responds to activity on DB0-DB7.

**Hold Mode:** The selected DAC latch retains the data which was present on DB0-DB7 just prior to  $\overline{DS}$  and  $R/\overline{W}$  assuming a high state. Both analog outputs remain at the values corresponding to the data in their respective latches.

**Read Mode:** When  $\overline{DS}$  is low and  $R/\overline{W}$  is high, the selected DAC is in the read mode and the data held in the appropriate latch is outputted to the data bus.

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**APPLICATION NOTES**

*Refer to Applications Section for Additional Information*